

FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary) Date Submitted to PTO: (DATE)			ATTY DOCKET NO. 03500.015727.		APPLICATION NO. 09/941,780	
APPLICANT Takeo Tsukamoto			FILING DATE August 30, 2001			
U.S. PATENT DOCUMENTS			GROUP 2821 2828			

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
Q	6,472,814 B1	10/02	Yamanobe et al.	313	495	11/13/98
↑	5,847,495	12/98	Yamanobe et al.	313	310	
	5,066,883	11/91	Yoshioka et al.	313	309	
	6,455,021 B1	09/02	Saito	423	447.3	07/20/99
	6,471,936 B1	10/02	Chen et al.	423	658.2	03/02/00
	6,283,812 B1	09/01	Jin et al.	445	24	01/25/99
	4,816,289	03/89	Komatsu et al.	423	447.3	
	5,443,859	08/95	Nagata	427	122	
	5,618,875	04/97	Baker et al.	524	495	
	5,690,997	11/97	Grow	427	249	
	6,129,602	10/00	Yamanobe	445	24	
	6,228,904 B1	05/01	Yadav et al.	523	210	
	6,333,016 B1	12/01	Resasco et al.	423	447.3	9/3/99
	6,413,487 B1	07/02	Resasco et al.	423	447.3	6/2/00
	6,445,006 B1	09/02	Brandes et al.	257	76	7/27/99
	5,981,305	11/99	Hattori	438	20	
	6,290,564 B1	9/01	Talin et al.	445	50	9/30/99
	5,458,784	10/95	Baker et al.	210	674	5/3/00
↓	6,331,690 B1	12/01	Yudasaka et al.	219	121.6	
Q	5,965,267	10/99	Nolan et al.	428	408	

EXAMINER David J. V.	DATE CONSIDERED 11/4/04
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EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
D	6,390,612 B1	05/02	Kotaki et al.	347	85	
↑	5,872,541	02/99	Yoshioka et al.	345	74	
	5,543,684	08/96	Kumar et al.	313	495	
	5,551,903	9/96	Kumar et al.	445	24	
	4,900,483	2/90	Witzke et al.	264	29.2	
	5,500,200	3/96	Mandeville et al.	423	447.3	
	5,726,524	3/98	Debe	313	309	
	2002/0009637 A1	1/24/02	Murakami et al	429	213	2/5/01
	2002/0047562 A1	04/25/02	Kitamura et al.	315	169.3	05/29/01
	5,770,918	6/98	Kawate et al.	313	495	
	5,185,554	2/93	Nomura et al.	313	495	
✓	2002/0146958 A1	10/02	Ono et al.	445	24	
D	2003/0048056 A1	3/03	Kitamura et al.	313	311	

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FOREIGN PATENT DOCUMENTS						
NO.	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
2	11-194134	07/99	Japan	G01N	37/00	Abst., European Equivalent 0 913 508 A3
1	11-139815	05/99	Japan	G01B	31/02	Abst.
	0 535 953 B1	01/96	EPO	H01J	1/30	English
	1 122 344 A2	08/01	EPO	D01F	9/127	English
	0 758 028 B1	09/11/02	EPO	D01F	9/127	English
	11-232997	08/27/99	Japan	H01J	1/30	European Counterpart 0 936 650
	1 022 763 A1	7/00	EPO	H01J	9/02	English
	2000-223005	8/00	Japan	H01J	1/304	Abst. & Counterpart U.S. Patent 6,283,812
	0 836 217 A1	04/98	EPO	H01J	29/94	English
	WO 99/58748	11/99	PCT	D01F	9/127	English
	CN 1181607A	5/98	China			English Counterparts 0 836 217 & 09/58748
	1 102 299 A1	5/01	EPO	H01J	1/30	English
	0 913 508 A3	5/99	EPO	D01F	9/127	English
	1 096 533 A1	5/01	EPO	H01J	9/02	English
	WO 01/26130	4/01	PCT	H01J	9/02	English
✓	GB 2 308 495 A	6/97	UK	H01J	1/20	English
2	1 120 877 A1	8/01	EPO	H02G	5/06	English

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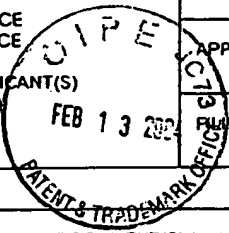
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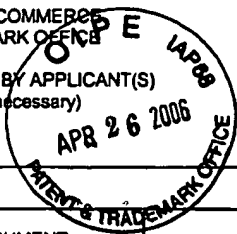
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1-309242	12/89	Japan	H01J	37/06	Abst.
11-162334	6/99	JAPAN	H01J	9/02	Abst.
2000-57934	2/00	JAPAN	H01J	1/304	Abst.
2000-86216	3/00	JAPAN	C01B	31/02	Abst.
2000-90809	3/00	JAPAN	H01J	1/304	Abst.
2001-288625 A	10/01	Japan	D01F	9/127	Abst., Counterpart U.S. Patent 2002/00809437 & EP 1 122 344
0 433 507 A1	6/91	EPO	D01F	9/127	English
03-260119	11/91	Japan	D01F	9/127	Abst. & Counterpart U.S. Patent 4,900,483
2001-52598	2/01	Japan	H01J	1/316	Abst.
2000-95509	4/00	Japan	C01B	31/02	Abst.
0 451 208 B1	3/00	EPO	D01F	9/12	English
2000-208028	7/00	Japan	H01J	1/304	Abst.
0 936 650 A1	8/01	EPO	H01J	3/02	English
08-298068	11/96	Japan	H01J	1/30	Abst.
2001-162600	6/19/01	Japan	B82B	1/00	Abst.

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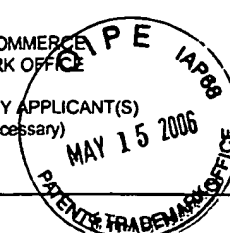
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LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)					
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)					
2		W. Zhu Et Al., <i>Electron Field Emission From Nanostructured Diamond and Carbon Nanotubes</i> , Solid State Electronics, Vol. 45, 2001, pp. 921-928			
↑		J.M. Bonard Et Al., <i>Field Emission From Carbon Nanotubes: The First Five Years</i> , Solid State Electronics, Vol. 45, 2001, pp. 893-914			
↑		A.M. Rao et al., "In Situ-grown Carbon Nanotube Array of with Excellent Field Emission Characteristics," Applied Physics Letter, Vol. 76, No. 25, pp. 3813-3815 (2000).			
↑		Cheol Jin Lee et al., "Carbon Nanofibers Grown on Sodalime Glass at 500 °C Using Thermal Chemical Vapor Deposition," Chemical Physics Letters 340, pp. 413-418 (2001).			
↓		Sashiro Uemura et al., "Carbon Nanotube FED with Graphite-Nano-Fiber Emitters," ISSN 1083-1312, pp. 398-401, 2000.			
2		Q. H. Wang et al., "A Nanotube-Based Field-Emission Flat Panel Display," Applied Physics Letters, Vol. 72, No. 22, June 1998, pp. 2912-2913			
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d		2003/0048057 A1	3/13/03	Oyama et al.	313	311	—
d		2002/0031972 A1	3/14/02	Kitamura et al.	445	3	—
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
d	JP	2000-207983	07/28/00	Japan	—	—	Abstract
d	JP	2002-500415	01/08/02	Japan	—	—	No
d	WO	01/93292 A1	12/6/01	PCT	—	—	English
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
d		Xucun Ma et al., Polymerized carbon nanobells and their field-emission properties, Applied Physics Letters, 15 Nov. 1999, Vol. 75, No. 20, pp. 3105-3107.					
EXAMINER		David VW			DATE CONSIDERED		
					7/10/06		

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D		6,624,589 B2	09/23/03	Kitamura et al.	315	169.3	
↑		6,628,053 B1	09/30/03	Den et al.	313	310	
		6,626,719 B2	09/30/03	Ono et al.	445	24	
		2002/0060516 A1	05/23/02	Kawate et al.	313	495	
		2002/0057045 A1	05/16/02	Tsukamoto	313	309	
		2002/0047513 A1	04/25/02	Nomura	313	495	
		2003/0006684 A1	01/09/03	Kawate et al.	313	311	
		2003/0048055 A1	03/13/03	Ishikura et al.	313	311	
↓		2003/0057860 A1	03/27/03	Tsukamoto	315	169.3	
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